

# RELIABILITY REPORT





NOW PART OF



# Reliability Data Report

## Product Family R577

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LTC4000 \ LTC4013 \ LTC4020 \ LTC4079 \ LTC4120 \  
LTC4121 \ LTC4123 \ LTC4124 \ LTC4126

# Reliability Data Report

## Report Number: R577

Report generated on: Fri Apr 10 18:49:39 PDT 2020

<b>OPERATING LIFE TEST</b>					
<b>PACKAGE TYPE</b>	<b>SAMPLE SIZE</b>	<b>OLDEST DATE CODE</b>	<b>NEWEST DATE CODE</b>	<b>K DEVICE HRS (+125°C)<sup>1</sup></b>	<b>No. of FAILURES <sup>2, 3</sup></b>
QFN/DFN	916	1302	1546	1619	0
Totals	916	-	-	1,619	0

<b>PRESSURE COOKER TEST AT 15 PSIG , +121 DEG C</b>					
<b>PACKAGE TYPE</b>	<b>SAMPLE SIZE</b>	<b>OLDEST DATE CODE</b>	<b>NEWEST DATE CODE</b>	<b>K DEVICE HRS</b>	<b>No. of FAILURES</b>
QFN/DFN	200	1537	1649	4	0
Totals	200	-	-	4	0

<b>TEMP CYCLE FROM -65 TO 150 DEG C</b>					
<b>PACKAGE TYPE</b>	<b>SAMPLE SIZE</b>	<b>OLDEST DATE CODE</b>	<b>NEWEST DATE CODE</b>	<b>K DEVICE CYCLES</b>	<b>No. of FAILURES</b>
QFN/DFN	198	1537	1649	19	0
Totals	198	-	-	19	0

<b>THERMAL SHOCK FROM -65 TO 150 DEG C</b>					
<b>PACKAGE TYPE</b>	<b>SAMPLE SIZE</b>	<b>OLDEST DATE CODE</b>	<b>NEWEST DATE CODE</b>	<b>K DEVICE CYCLES</b>	<b>No. of FAILURES</b>
QFN/DFN	200	1537	1649	20	0
Totals	200	-	-	20	0

<b>HIGH TEMPERATURE BAKE AT 150 DEG C</b>					
<b>PACKAGE TYPE</b>	<b>SAMPLE SIZE</b>	<b>OLDEST DATE CODE</b>	<b>NEWEST DATE CODE</b>	<b>K DEVICE HRS</b>	<b>No. of FAILURES</b>
QFN/DFN	100	1537	1537	100	0
Totals	100	-	-	100	0

<b>HIGH TEMPERATURE BAKE AT 175 DEG C</b>					
<b>PACKAGE TYPE</b>	<b>SAMPLE SIZE</b>	<b>OLDEST DATE CODE</b>	<b>NEWEST DATE CODE</b>	<b>K DEVICE HRS</b>	<b>No. of FAILURES</b>
QFN/DFN	100	1537	1537	50	0
Totals	100	-	-	50	0

(1) Assumes Activation Energy = 0.7 Electron Volts  
 (2) Failure Rate Equivalent to +55 °C, 60% Confidence Level =7.32 FITS  
 (3) Mean Time Between Failure in Years = 15597.64

Note: 1 FIT = 1 Failure in One Billion Hours.

Note 2: HAST, Temp Cycle & Thermal Shock are subjected to J-STD-020 MSL1 Preconditioning